

Message from the ARFTG Chairs

The 69th Automatic RF Techniques Group (ARFTG) Microwave Measurement Conference will be held at the Hilton Hawaiian Village on Friday, 8 June 2007. The conference theme is “Addressing Metrology Needs for Future High-Speed Information and Communication Systems.”

Dr. Wolfgang Heinrich from FBH Berlin will kick off the conference with a keynote speech on the emerging topic of “Characterization Challenges for Future Base-Station Power Amplifiers.” Regular papers will focus on wideband measurements for high-speed communication systems, digital communication system metrics, complex waveform analysis, linear and nonlinear vector network analysis, multiport and differential measurements, and other areas of microwave and millimeter-wave measurements.

As the ARFTG paper submission deadline is traditionally in February, the ARFTG technical program was not available at the time of printing, so attendees are referred to the ARFTG website www.arftg.org for the latest updates. The 69th ARFTG conference will be the first ARFTG Spring Conference without a paper digest. Technical papers will be included in the ARFTG section on the IMS CD-ROM and an abstract book will be provided to the attendees.

There are two other CD-ROMs that can be purchased through on-line or on-site registration: the brand new ARFTG Workshop Compendium CD-ROM, covering all Fall ARFTG Nonlinear Measurements Workshops to date (2001–2006), and the ARFTG Conference Compendium CD-ROM.

The conference will be preceded on Thursday by the Nonlinear Vector Network Analyzer (NVNA) Users’ Forum, an informal discussion group devoted to sharing information and issues related to instrumentation utilized in vector large-signal analysis of microwave circuits and systems that contain nonlinear elements. All interested are welcome to attend.

Also, be sure to check out the joint ARFTG/IMS workshops. ARFTG is cosponsoring and coorganizing two workshops on Monday: “WMA: Advances in Active Device Characterization and Modeling for RF and Microwave” and “WMC: High-Speed Digital Signal Integrity.”

An important part of all ARFTG Conferences is the opportunity to interact one-on-one with colleagues, experts, and vendors in the RF and microwave test and measurement community. Starting with the continental breakfast in the exhibition area, continuing through the two exhibition/interactive forum sessions and the luncheon, there will be ample opportunity for discussion with others facing similar challenges. So, come and join us. You’ll find that the atmosphere is informal, open, and friendly.



Dominique Schreurs
Conference Chair
69th ARFTG Conference



Uwe Arz
Technical Program Chair
69th ARFTG Conference